

Design obfuscation versus test

Farahmandi, Farimah; Sinanoglu, Ozgur; Blanton, Ronald; **Pagliarini, Samuel Nascimento** 2020 IEEE European Test Symposium (ETS) : ETS 2020, May 25 - 29, 2020, Tallinn, Estonia 2020 / 10 p <https://doi.org/10.1109/ETS48528.2020.9131590>

An overview of FPGA-inspired obfuscation techniques

Abideen, Zain Ul; Gokulanathan, Sumathi; Aljafar, Muayad J.; Pagliarini, Samuel Nascimento arXiv.org 2023 / 30 p. : ill <https://doi.org/10.48550/arXiv.2305.15999>